## Notice of References Cited Application/Control No. 10/757,405 Examiner David E. Martinez Applicati(s)/Patent Under Reexamination TAKINOSAWA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0225796	11-2004	Hanson et al.	710/301
*	В	US-2001/0006902	07-2001	Ito, Takafumi	455/558
*	С	US-6,748,482	06-2004	Fackenthal, Richard E.	711/103
	D	US-			
	Ш	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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